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## A Petrological Study on the Basalts of Hyogo Prefecture, Japan

## Part I. X-ray Microanalysis of Clinopyroxenes

## By

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#### Abstract

X-ray microanalysis has been made quantitatively on the clinopyroxenes from the basalts of the Quarternary Period in Hyogo Pref. to determine their composition of Na<sub>2</sub>O, MgO, Al<sub>2</sub>O<sub>3</sub>,  $\text{SiO}_2$ ,  $\text{TiO}_2$ , MnO and FeO (or Fe<sub>2</sub>O<sub>3</sub>) by use of the reference standard of the augite phenocryst in the andesite of Nisekarita, Mt. Zao. Owing to the simiiarity in composition between the standard and the unknowns, analysis has been carried out directly comparing the accumulated X-ray counts obtained from the standard and the unknowns.

Oxide totals show good results having errors of only  $3\%$  or less and these errors should be attributed mainly to chemical diversity in analyzed grains, discordancy between area bombarded by electron and pyroxene grain to be analyzed, and X-ray source size.

Quantitative results were also calculated into Wo-En-Fs-percent and atomic percent with respect to Ca, Mg and  $(Fe^{+2}+Fe^{+3}+Mn)$  atoms and these pyroxenes were determined to be diopside-diopsidic augite.

Although further refinement of analytical techniques is required to decrease errors equivalent to statistical errors, these good results give a promise of satisfactory applications of the microanaiyser to routine analysis in mineralogy and petrology.

## Introduction

Basalts in the Kinki District of the Quarternary Age have been studied occasionally by the students of Kyoto University, i.e., S. KOKAWA<sup>1</sup>, and recently by Y. Ochi<sup>2</sup> of Fukuoka University of Arts and Sciences.

 The authors, having participated in the Upper Mantle Project, are now investigating the rocks of this kind from Kyogo Pref., and these results will be reported in succession hereafter.

Generaliy speaking, the chemical composition of each main constituent mineral

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in a rock must be accurately and precisely determined petrologically. However, in volcanic rocks such as basalt and andesite, constituent minerals, especially groundmass minerals, are generally of very fine grain. Therefore, samples of such a fine grained mineral free from other rninerals and convenient for the determination of its chemical composition are very difficult to be acquired. Such determination under the microscope, i.e., optical determination of these fine-grained minerals, cannot be done with high accuracy.

Accordingly, X-ray microanalysis is required in such a case, because X-ray microanalyser, by applying a finely focused electron beam (approximately  $l<sub>\mu</sub>$  or less) to a particular point of the surface of the specimen whose chemical composition is to be examined, enables qualitative or quantitative analysis non-destructively.

This method is very useful for mineralogy and petrology because of elimination of time-loss, high spatial resolution and unnecessity of tedious mineral separation. If the minerals forming rocks can be analyzed individually with high accuracy by use of microanalyzer, studies of the magmatism and the regional and therma} metamorphism of rocks will be greatly promoted.

 There have been made a few reports (3-6) on the quantitative analysis of rock-forming minerals by microanalyzer, but most of them deal with synthetic minerals and seml-guantitative analysis.

This paper deals with quantitative analysis of natural clinopyroxenes from the basalts mentioned above making use of the methods of direct comparison with augite phenocryst of already-known composition as the reference standard.

The field survey of this study has been performed by H. YosHIZAWA and K. ISHIZAKA, the microscopical observation mainly by S. NISHIDE, the analysis of the bulk chemical composition of their rocks by K. NisHiMiyA and X-ray microanalysis of their minerals by T. WAKABAYASHI assisted by T. TAKASE. These experiments have been directed by H. YosHIZAWA.

#### Standard and unknown specimens

Five unknown specimens of basalt have been used in this study, whose localities are Izoe, Mikata-cho (# 10), Ikeyama, Oya-cho (#22), Kannabe, Hidaka-cho  $(\sharp 33)$ , Gembudo, Toyooka-city ( $\sharp 41'$ ) and Yakuno, Santo-cho ( $\sharp 51$ ).

 These basalts consist of olivine and plagioclase as phenocrysts, and of olivine, clinopyroxene and plagioclase in groundmass, occassionally accompanied by biotite, anorthoclase and glass as mesostases. No orthopyroxene is observed in these specimens. The optical micrographs of these basalts are shown in Fig. 1.

 For the microanalysis of these groundmass clinopyroxenes, it ls convenient to use as reference standard a pyroxene resembling the pyroxenes to be analyzed as



Fig. 1. Microphotograph of the Basalts ( $\times$ 31ca.) Phenocryst **···**olivine (mainly) and plagioclase. Groundmass…olivine, clinopyroxene, plagioclase, biotite, alkali-feldspa magnetite and glass.



 $#55$ 

Opened

Crossed



Table 1. Gravimetric analysis of the standard pyroxene\*

closely as possible in its composition in order to be able to ignore the absorption of the X-rays by their specimens, fiuorescence excitation by the line radiation and by the continuous X-ray and also the atomic number effect by the specimens.

The clinopyroxene used as the standard is the augite phenocryst in an orthopyroxene-bearing augite andesite from Nisekarita, Mt. Zao, Yamagata Pref., kindly given to the authors by T. TIBA, K. Aoki and H. ONUKI.

The composition of the standard shown in Table I was determined chemicaily by these three scholars. The quantitative microanalysis of this standard will be discussed by one of the authors (T. X/VAKABAyAsm) in near future.

## Experimental Procedures

Each basalt specimen was broken into fragments of appropriate size and embedded in black bakeiite of one inch diameter together with the standard pyroxene grain.

Polishing was done, by using, in order, 180-, 320-, 400- and 600 grid carborundum on rotating adhesive-paper laps with water, and then 5-, 0.3- and O.05 microns alumina on rotating soft cloth laps with water.

The time required for polishing totaled more than 100 minutes. The reason for polishing with such particular care is to avoid errors arising from irregularities on the specimen surface. Of course, the microanalyzer employed, having a high take-off angle of  $52.5^{\circ}$ , is far less sensitive to inaccuracies due to surface irregularities than the microanalyzer with a smaller X-ray take-off angle, but errors may stil} result if the irregularities are strongly pronounced, especially in the case of weak radiation such as Na $K_{\alpha}$ .

 The specimens were throughly cleaned and freed of abrasive particles and dirts by using a rotating soft cloth, with slight nap, wet with water, and then dried with air. Then, to give the electrical and thermal conductivity, coating is made on the standard and the unknown specimens simultaneously and at the same distance from the source by vacuum evaporation, covering with carbon layer of about 200A thickness.

<sup>\*</sup> Data of the chemical cornposition of this Zao's pyroxene, having not yet been published, wereadopted here by courtesy of T. TibA, K. Aoki and H. ONUE

 For mounting these specimens brass specimen holder is used, which is designed so that the polished surface of the specimens may be mounted in the proper orientation.

 The microanalyzer employed in this study, having three spectrometers of a type having directly readable wavelength with the X-ray take-off angle shown above, permits three elements to be analyzed simultaneously.

The selection of spectrometer were made as follows: for  $Fek\alpha$ ,  $MnK\alpha$  and TiK $\alpha$ , 4 inch radius LiF spectrometer and "Exatron" counter using Kr gas and 0.01 inch Be window were employed; for CaK $\alpha$  and SiK $\alpha$ , 4 inch radius ADP spectrometer and "Exatron" counter using Ne gas and O.01 inch Be window were employed; for AlK $\alpha$ , MgK $\alpha$  and NaK $\alpha$ , 4 inch potassium acid phthalate crystal and flow proportional counter with an ultrathin nitrocellulose window using an argon-methane  $(P - 10)$  flow gas were employed.

 Spectrometers were aligned carefully for the analysis of the appropriate elements for pyroxenes, in the combinations as shown next: (a)  $Fek_{\alpha}$ , CaK $_{\alpha}$  and MgK $_{\alpha}$ , (b) MnK $\alpha$  and NaK $\alpha$ , (c) TiK $\alpha$  and AIK $\alpha$ : the elements forming each group were analyzed simultaneously before changing into a new setting for the monochromator.

For analyzing these elements, the effect of wave-length shift in the characteristic X-ray lines was left out of consideration because of similarity of the composition.

 The excitation condition was decided considering the X-ray yield and resolution: A high accelerating voltage brings a greater X-ray yield, but gives a lower resolution, so that the excitation condition must be decided according to the purpose of analysis. For this analysis, an accelerating voltage of  $20 \text{ KV}$ , together with a specimen current of 0.08  $\mu$ A, was used considering the excitation voltage of 7.1 KeV for FeK $\alpha$  and the minimum size of incident electron beam of about 0.5 $\mu$ .

 Since all the specimens were coated with carbon iayer it was difficult to decide their pyroxenes with the reflection microscope of this apparatus. Consequently, X-ray scanning pictures were taken for each element, by which the existing positions of pyroxene on the graticule of oscilloscope were decided. Incident electron beam upon these specimens was deflected electrically so as to strike pyroxene.

Ten of the pyroxenes were selected for each basalt specimen and each generating X-ray quanta was accumulated in 20 seconds by using scalers so as to yield a small enough statistical error. The analysis spots for Fe, Ca and Mg did not correspond to the spots for Mn and Si, and also Ti, Al and Na. For the analysis of the standard pyroxene, ten spots were also selected; in this case, endeavor was made to avoid the inclusions of hypersthene.

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## Results and Discussions

 Fig. 2 shows X-ray scanning pictures of # 33 basalt specimen, as an example, taken for each element in order to decide minerals composing basalt: The scanning picture of the specimen current, also, is shown in Fig. 2.

 In general, basalt is composed of olivine, pyroxenes, plagioclase and magnetite (or ilmenite). Having a distinctive feature of being rich in MgO and CaO together



(a) specimen current

## (b) Fe $K\alpha$

(c)  $MnK\alpha$ 



(d) TiK $\alpha$ 

(e)  $CaK\alpha$ 

(f) Si $K_{\alpha}$ 







Fig. 3. Schematic Illustration for the distribution of minerals in the basalt  $(\frac{1}{2}33)$ 





Note: 1) compositions (SiO<sub>2</sub>, TiO<sub>2</sub> etc.) are shown in weight precent.<br>
2) Ca, Mg and (Fe<sup>+2</sup>+Fe<sup>+3</sup>+Mn) are shown in atomic percent.<br>
3) \* The standard specimen contains 2.92% of Fe<sub>2</sub>O<sub>3</sub>.<br>
4) \*  $\neq$  41' is an mixtur method.

with SiO<sub>3</sub>, monoclinic pyroxene can be found by searching the grains of high intensity for MgK $\alpha$  and CaK $\alpha$  together with SiK $\alpha$ . In a similar way, all minerals composing basalt were found from X-ray scanning pictures as illustrated schematically in Fig. 3.

Table II contains the data of X-ray microanalyses of the monoclinic pyroxenes from each basalt in weight percent, and also the individual atomic percent with respect to Ca, Mg and  $(Fe^{+2}+Fe^{+3}+Mn)$  atoms (Fig. 4) and weight percent of each pyroxene molecuie.



Diagram.

 Although an important question arises concerning the state of oxidation of iron in pyroxene, it was impossible in this study to divide Fe into FeO and  $Fe<sub>o</sub>$ , accurateiy since oxygen was not measured. However, the Total (I) inTable II shows better results compared with Total (II), therefore, it is considered that most of the total Fe in each pyroxene in this study have the divalent form rather than the trivalent form.

Judging from the results obtained by the microanalysis, the pyroxenes from

the basalts (#10, #22, #33, and 51), except for one (#41') are obviously diopside to diopsidic augite, and this fact agrees with the data obtained from the optical microscopical observations which will be discussed in Part II.

As these pyroxenes in question abound in  $\text{Na}_2\text{O}$  and  $\text{TiO}_2$  slightly more than common diopside and augite, they distinctly have, in some degree, the molecules of titanaugite and acmite.

As for the accuracy of the analyses, the Total (I) gives the resultant errors of  $2\%$  ca; moreover, an error from K<sub>a</sub>O is to be expected if K<sub>a</sub>O is measured, but it will be trivial. Although there is no doubt that the error of  $2\%$  is satisfactory for routine work, the promotion of accuracy can be expected by inspecting the sources of error.

$Com-$ position	Standard			$\neq 10$		$\neq 22$		$= 33$		$\neq$ 41'		$\neq 51$	
	$C_{\mathbf{w}}$ %	$\sigma_1$ $\frac{96}{1}$	$\sigma_{2}$ $\frac{2}{\%}$	$C_{\mathbf{x}}$ /	$\sigma_{2_{\frac{\omega_{\ell}}{2}}}$	$C_{\mathbf{x}}$ /2	$\sigma_{2_{\frac{\gamma}{6}}}$	$\mathbf{C}_{\mathbf{x}_{g}^{(n)}}$	$\sigma_{2_{\widetilde{\mathscr{C}}}}$ ,	$\mathbf{C}_{\mathbf{x}_{\underline{\mathscr{G}}}+}$	$\sigma_{2_{\mathscr{Y}_{1}}}$	$C_{\mathbf{x}_{g}$	$\sigma_{\stackrel{\phantom{.}\smash{\partial}}{\mathscr{Y}}\!\!\mathscr{Y}}$
SiO <sub>2</sub>	50.04	0.12	0.15	50.3	0.45	50.2	0.48	49.2	0.50	41.5	0.41	50.6	0.40
TiO <sub>2</sub>	1.07	0.01	0.05	1.71	0.10	1.86	0.15	2.79	0.11	7.22	0.19	2.60	0.38
$\text{Al}_2\text{O}_3$	3.19	0.07	0.22	4.54	0.30	3.29	0.32	4.48	0.28	7.72	0.44	3.95	0.34
FeO	$12.87*$	0.04	0.12	9.54	0.28	9.60	0.27	10.1	0.32	12.7	0.40	9.84	0.51
MnO	0.31	0.00	0.01	0.34	0.00	0.29	0.00	0.24	0.00	0.25	0.01	0.33	0.01
MgO	14.30	0.06	0.13	15.0	0.43	14.9	0.38	13.2	0.25	9.71	0.60	13.9	0.49
CaO	17.95	0.03	0.10	16.9	0.60	20.2	0.59	20.9	0.43	20.6	0.73	18.8	0.60
Na <sub>2</sub> O	0.44	0.01	0.03	0.94	0.03	0.68	0.02	0.87	0.02	1.24	0.04	0.87	0.03
Total	100.17	0.34	0.81	99.3	2.19	101.0	2.21	101.8	1.91	100.9	2.82	100.9	2.76

Table III. Errors arised from statistical variation, chemical difference in each analysis point and positional discordancy between area bombarded by electron and pyroxene-grain, calculated by the method of Least Squares.

Notes 1) \* Contains 2.92% of  $Fe<sub>2</sub>O<sub>3</sub>$ 

2)  $C_w$  and  $C_x$  represent the compositions by wet chemical analyses and X-ray microanalyses respectively.

3)  $\sigma_1$  represnets statistical errors.  $\sigma_2$  represents errors arised from statistical variation, chemical difference in analysis point and positional discordancy between area bombarded by electron and that of pyroxene-grain.  $\sigma_1$  and  $\sigma_2$  are calculated in weight percent.

4) K<sub>2</sub>O was undetermined.

Sources of error are considered as follows:

Statistical error-Analyses were made under the accelerating voltage of a) 20KV and the sample current of  $0.08<sub>\mu</sub>A$ , and these conditions would yield a small enough statistical error for 20 seconds accumulation of quanta, but statistical error must be considered for the elements of low concentration such as Na, Al, Ti and Mn. Resultant statistical error  $\sigma_1$  shown in Table III was obtained from the standard pyroxene by measuring ten times at the same spot of one crystal by calcu-

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lating by the method of least squares. As the amount of statistical error is  $0.34\%$ and small enough in comparison with resultant analyzed error of  $2-3\%$ , it is considered that the statistical error does not constitute one of the main source of error. b) Compositional diversity between different analyzed grains-Analyses were made ten times on each different setting of monochromator, that is (a) Fe, Ca, Mg, (b) Mn, Si, Na and (c) Ti, Al. Errors arising from the chemical diversity between different analyzed grains or analyzed points are shown in Table III as  $\sigma_2$  for each oxide. Each  $\sigma$ , was obtained from ten different grains or ten different points by the method of least squares. As  $\sigma_z$  contains, moreover, errors arising from discordance of positions between striking electron beam and pyroxene to be analyzed as discussed in the following (in c), it has a large value of about  $2-3\%$  and it is considered to be a main source of error: However, even if the error  $\sigma_2$  is attributed mainly to the diversity of the chemical composition between eack analyzed grain, it is important that the errors due to the diversity do not exceed  $3\%$ .

c) Positional discordancy between bombared part and pyroxene grain to be analyzed may bring large errors-For the analysis of pyroxenes, X-ray scanning pictures were taken for each element as mentioned previously. However, the size of each pyroxene grain is small, and is generally several m!crons or less, so that the incident beam is apt to strike partially on other minerals at the same time.\*

d) X-ray source size-Accelerated electrons penetrate into specimen surface. The higher the electron energy is, the deeper electron penetrates into specimen, and deeper penetration means a larger X-ray source size. The approximate vaiue of the depth of analyzed region Zm was expressed by Castaing (7) as foliows:

$$
Zm = 0.033 (V^{1.7} - Vk^{1.7}) \frac{A}{\rho Z}
$$
 microns,

where  $V$  and  $Vk$  are respectively accelerating voltage and excitation voltage expressed in kilovolts;  $A$  is the mean atomic weight of the bombarded point,  $Z$  is its mean atomic number, and  $\rho$  the local density in grams per cubic centimeter. Then, the diameter of the actual analyzed region is expressed as  $\delta = d + Zm$ , d is the beam size of the incident electron. In this study accelerating voltage of 20KV yields  $Zm$  of 2.5  $\mu$  to 3.2  $\mu$  for FeK $\alpha$  to NaK $\alpha$ , therefore  $\delta$  amounts to about 3  $\mu$ . Of course, the effective X-ray source size may be smaller than  $\delta$ due to absorption effect, X-ray source size may cause errors in case of analyzing pyroxenes smaller than  $3 \mu$  in grain size.

e) Chemical analyses of the standard sample-The standard pyroxene includes

<sup>\*</sup> The pyroxenes of the basalts (#41') are very fine grained ( $\leq l\mu$ ) compared with other specimens and, moreover, coexist intimately with ilmenite, judging from their microscopical observation. Therefore,  $\#41'$  basalt is considered to show the largest  $\sigma_2(2.82)$ .

some impurities of hypersthene and gives the gravirnetric chemical analysis error of  $0.45\%$  as shown in Table I (the standard specimen). Hence, microprobe analyses give fundamentally at least  $0.45\%$  of error.

f) Other sources of error-Many other sources of error are considered such as damage of carbon Iayer, contamination, finite resolving power of the detector or associated electronics etc., but they are considered to be trivial in this study in comparison with the error sources discussed above, and do not affect seriously the accuracy of microprobe analyses.

In conclusion, it can be said that chemical diversity in analyzed grains, positional discordancy between bombarded part and pyroxene grain to be analyzed and X-ray seurce size cause most of the analytical errors. The total possible errors amount to about 2-3% in maximum. Hence, since the statistical error is  $0.34\%$ , if an ideal analysis is made by avoiding these sources of error, resultant error of microprobe analysis will be lowered to less than  $0.34\%$ , i.e. statistical error under the measuring conditions adopted in this study.

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